

General Description

- Trench Power MV MOSFET technology
- Low $R_{DS(ON)}$
- Low Gate Charge
- Optimized for fast-switching applications

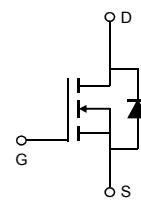
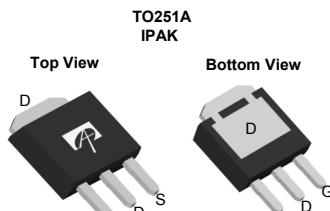
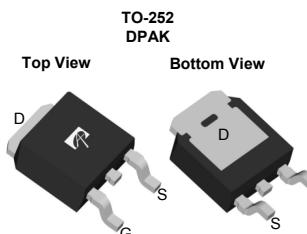
Product Summary

V_{DS}	200V
I_D (at $V_{GS}=10V$)	18A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 105mΩ
$R_{DS(ON)}$ (at $V_{GS}=5V$)	< 120mΩ

Applications

- Synchronous Rectification in DC/DC and AC/DC Converters
- Industrial and Motor Drive applications

100% UIS Tested

 100% R_g Tested


Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOD2210	TO-252	Tape & Reel	2500
AOI2210	TO-251A	Tube	4000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	200	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	$T_C=25^\circ C$	18	A
Current		13	
Pulsed Drain Current ^C	I_{DM}	45	
Continuous Drain Current	$T_A=25^\circ C$	3.0	A
		2.5	
Avalanche Current ^C	I_{AS}	9	A
Avalanche energy $L=0.1mH$ ^C	E_{AS}	4	mJ
V_{DS} Spike	10μs	V_{SPIKE}	V
	$T_C=25^\circ C$	100	W
Power Dissipation ^B		50	
	$T_A=25^\circ C$	2.5	W
Power Dissipation ^A		1.6	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10s$	$R_{\theta JA}$	15	20	°C/W
Maximum Junction-to-Ambient ^{AD} Steady-State		41	50	°C/W
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	1	1.5

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	200			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=200\text{V}, V_{GS}=0\text{V}$		1		μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$		5		nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.5	2.0	2.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=18\text{A}$		87	105	$\text{m}\Omega$
			$T_J=125^\circ\text{C}$	185	225	
		$V_{GS}=5\text{V}, I_D=16\text{A}$		93	120	
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=18\text{A}$		40		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
I_S	Maximum Body-Diode Continuous Current				18	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=100\text{V}, f=1\text{MHz}$		2065		pF
C_{oss}	Output Capacitance			74		pF
C_{rss}	Reverse Transfer Capacitance			3.8		pF
R_g	Gate resistance	$f=1\text{MHz}$	1.1	2.2	3.3	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=100\text{V}, I_D=18\text{A}$		27	40	nC
$Q_g(4.5\text{V})$	Total Gate Charge			12	20	nC
Q_{gs}	Gate Source Charge			7		nC
Q_{gd}	Gate Drain Charge			3		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=100\text{V}, R_L=5.5\Omega, R_{\text{GEN}}=3\Omega$		8		ns
t_r	Turn-On Rise Time			10		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			30		ns
t_f	Turn-Off Fall Time			4		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=18\text{A}, dI/dt=500\text{A}/\mu\text{s}$		60		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=18\text{A}, dI/dt=500\text{A}/\mu\text{s}$		800		nC

A. The value of R_{QJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\text{QJA}} \approx 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$.

D. The R_{QJA} is the sum of the thermal impedance from junction to case R_{QJC} and case to ambient.

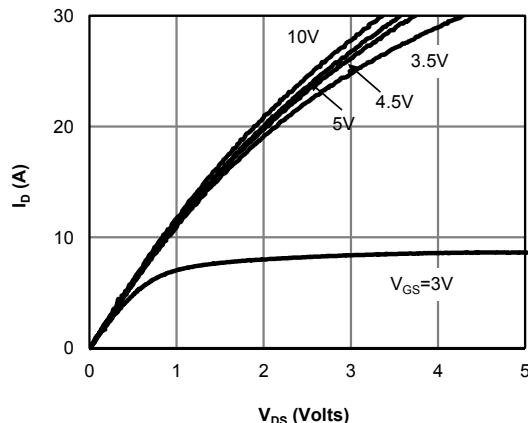
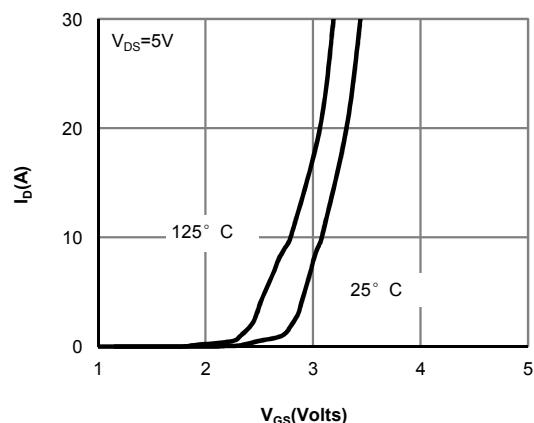
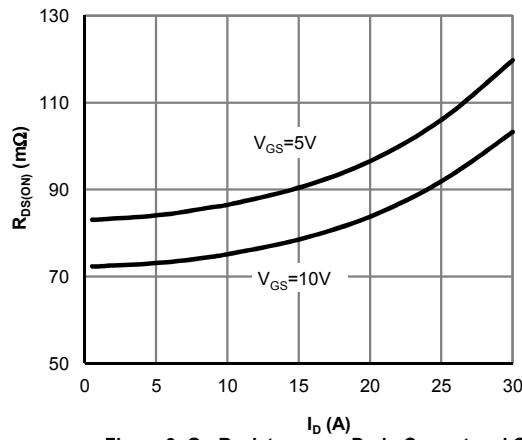
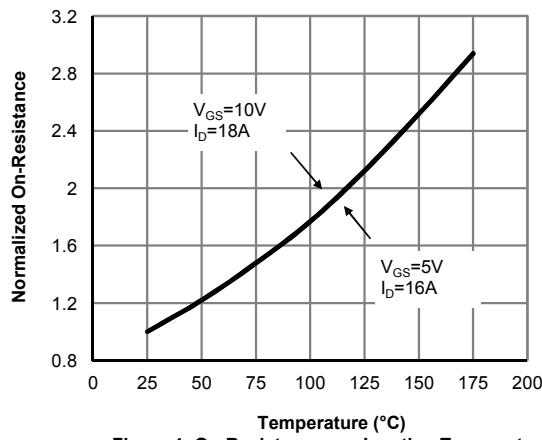
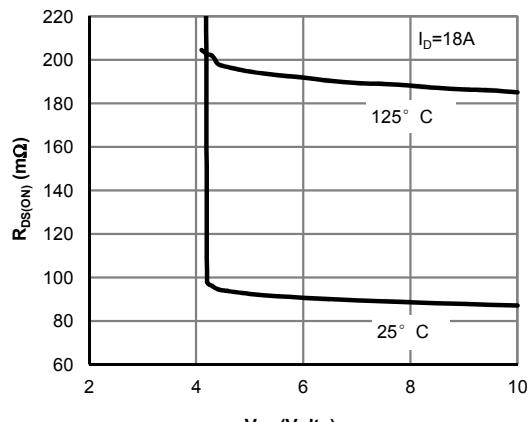
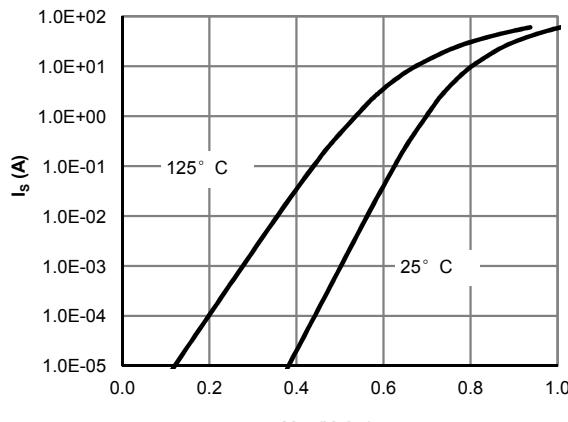
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

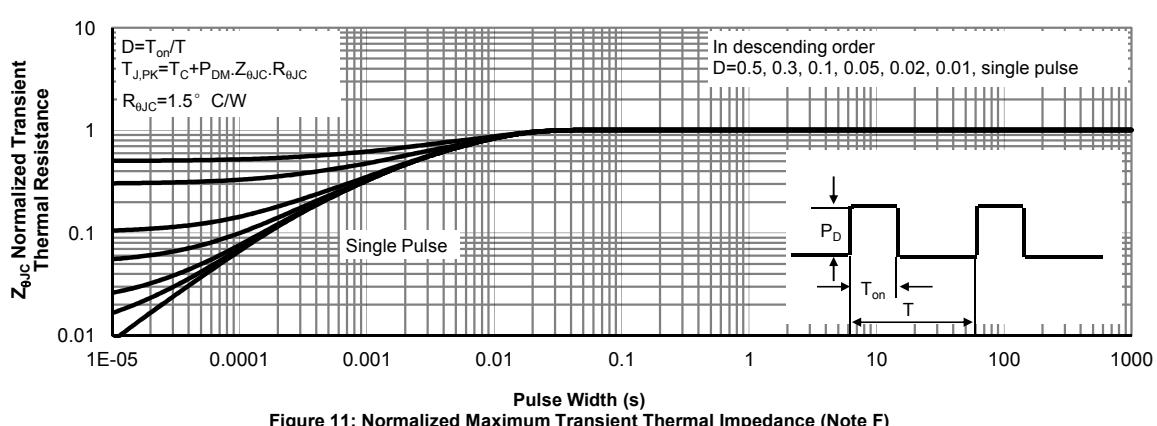
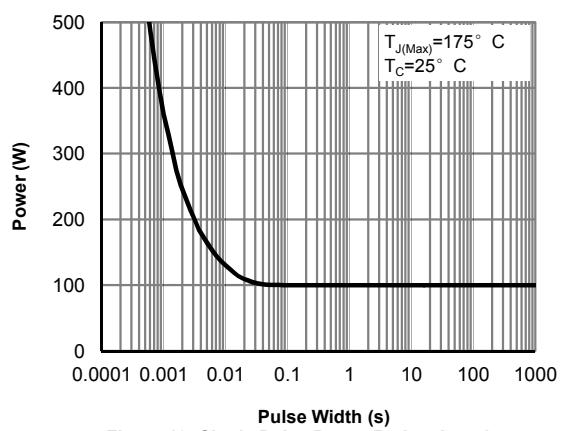
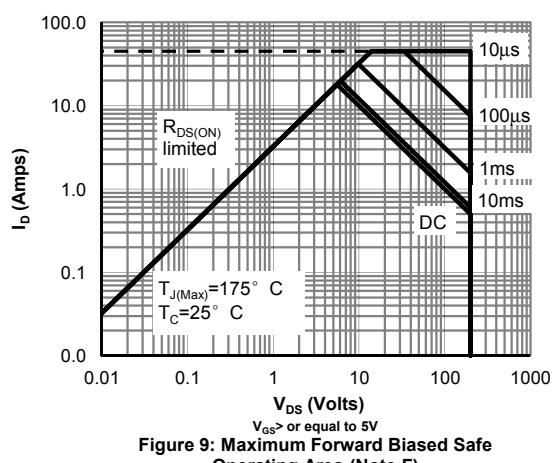
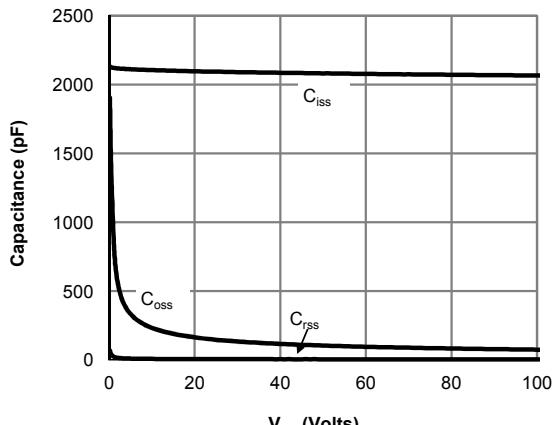
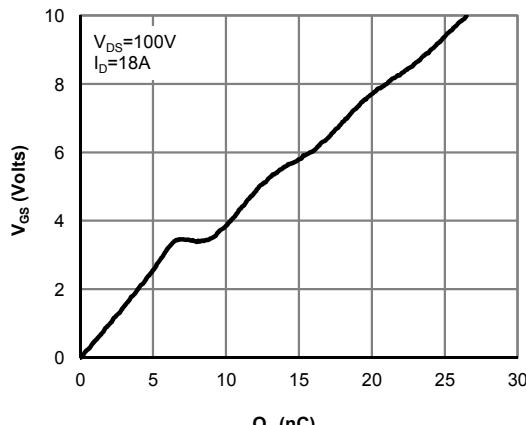
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{C}$. The SOA curve provides a single pulse rating.

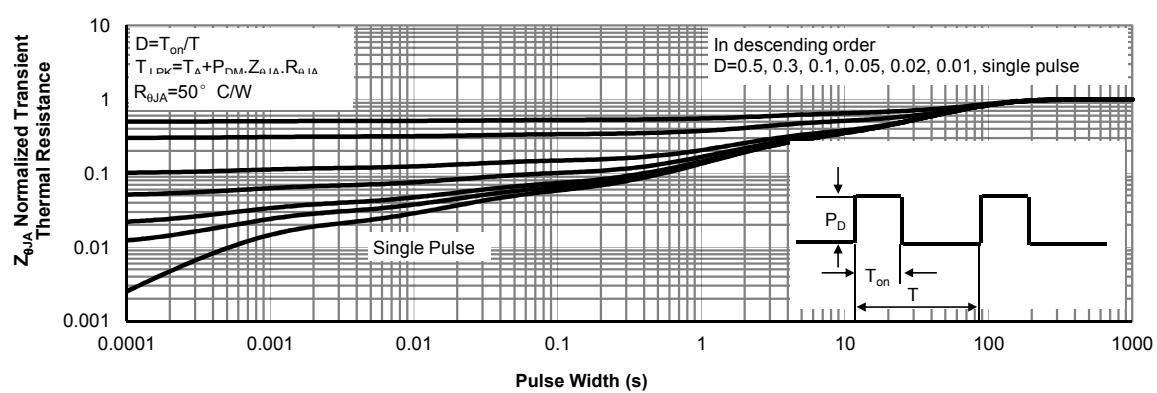
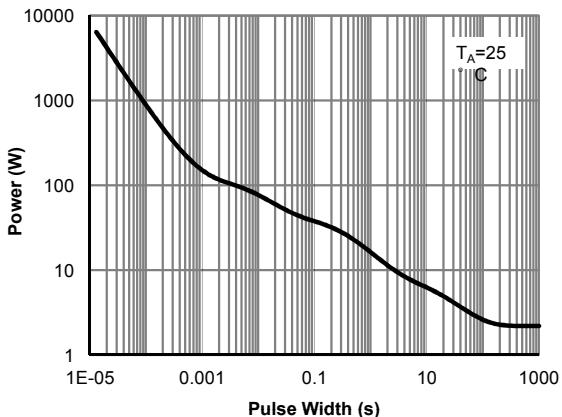
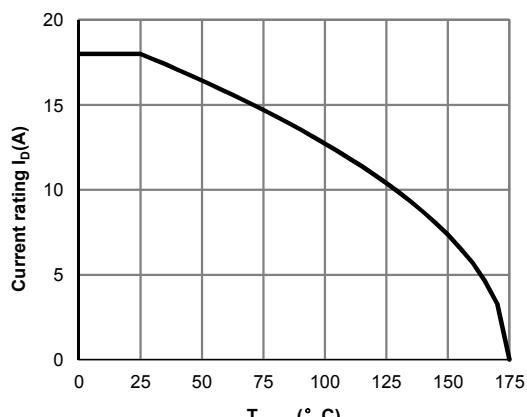
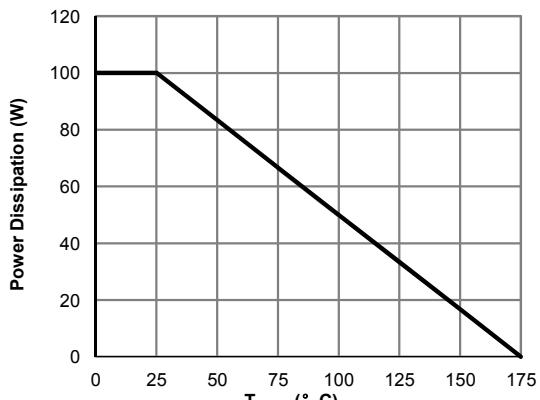
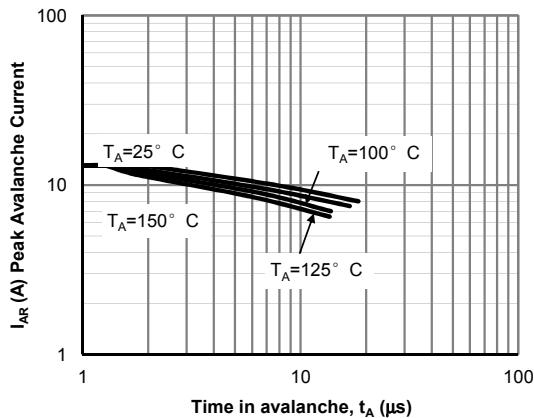
G. The maximum current rating is package limited.

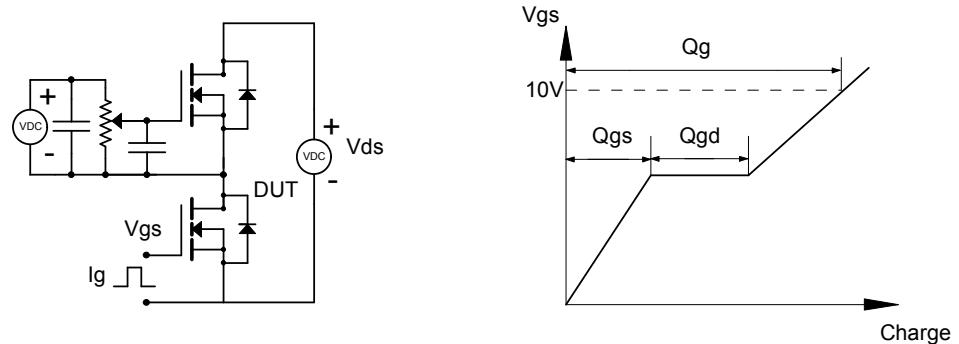
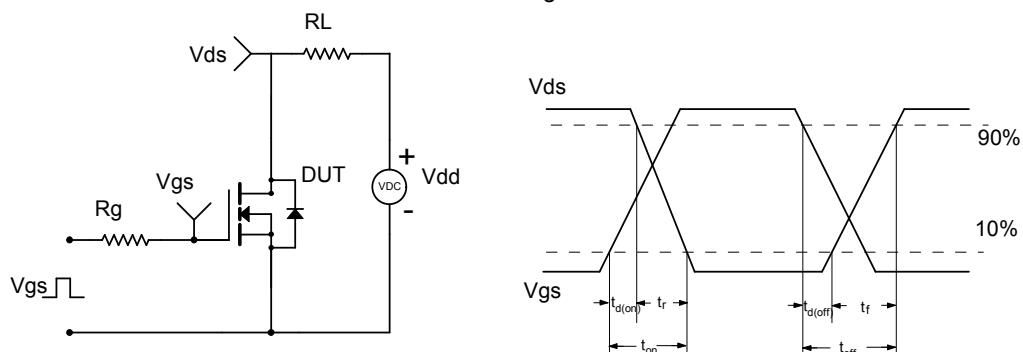
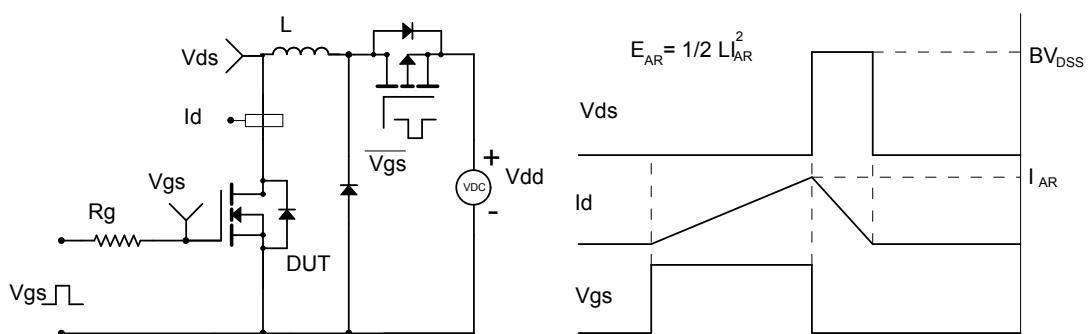
H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
